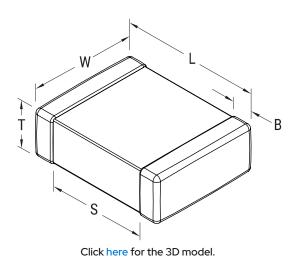


C1812C223KCRACTU

Aliases (C1812C223KCRAC7800)

SMD Comm X7R HV, Ceramic, 0.022 uF, 10%, 500 VDC, X7R, SMD, MLCC, High Voltage, Temperature Stable, 2.3 mm, 1812 / 4532



General Information	
Series	SMD Comm X7R HV
Style	SMD Chip
Description	SMD, MLCC, High Voltage, Temperature Stable
Features	High Voltage
RoHS	Yes
Termination	Tin
Marking	No
AEC-Q200	No
Typical Component Weight	95 mg
Shelf Life	78 Weeks
MSL	1

Dimensions			
L	4.5mm +/-0.3mm		
W	3.2mm +/-0.3mm		
Т	1mm +/-0.10mm		
S	2.3mm MIN		
В	0.6mm +/-0.35mm		
Case Code (EIA / mm)	1812 / 4532		

1000

Packaging Quantity

	W	3.2mm +/-0.3mm	Measurement Condition	TKHZ
	Т	1mm +/-0.10mm	Tolerance	10%
	S	2.3mm MIN	Voltage DC	500 \
	В	0.6mm +/-0.35mm	Dielectric Withstanding Voltage	750 \
	Case Code (EIA / mm)	1812 / 4532	Temperature Range	-55/+
			Temp. Coefficient	X7R
Packaging Specifications			Capacitance Change with	15%, 1
Packaging	Packaging	T&R, 180mm, Plastic Tape	Reference to +25°C and 0 VDC	

Specifications	
Capacitance	0.022 uF
Measurement Condition	1 kHz 1.0Vrms
Tolerance	10%
Voltage DC	500 VDC
Dielectric Withstanding Voltage	750 VDC
Temperature Range	-55/+125°C
Temp. Coefficient	X7R
Capacitance Change with Reference to +25°C and 0 VDC Applied (TCC)	15%, 1kHz 1.0Vrms
Dissipation Factor	2.5% 1 kHz 1.0Vrms
Aging Rate	3% Loss/Decade Hour: Referee Time is 1000 Hours
Insulation Resistance	45.4545 GOhms

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